Dual P-Channel 30-V (D-S) MOSFET

CHARACTERISTICS

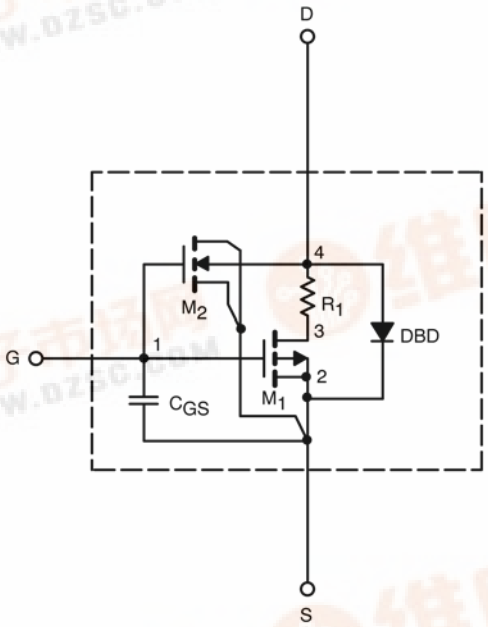
- P-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the –55 to 125°C Temperature Range
- Model the Gate Charge, Transient, and Diode Reverse Recovery Characteristics

DESCRIPTION

The attached spice model describes the typical electrical characteristics of the p-channel vertical DMOS. The subcircuit model is extracted and optimized over the –55 to 125°C temperature ranges under the pulsed 0 to 10V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched C_{gd} model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

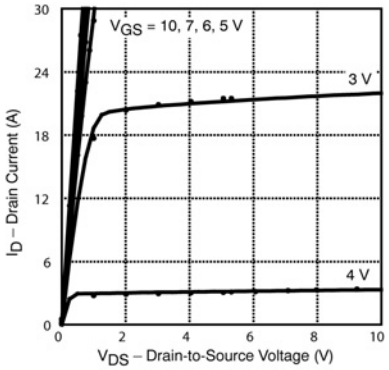
SUBCIRCUIT MODEL SCHEMATIC

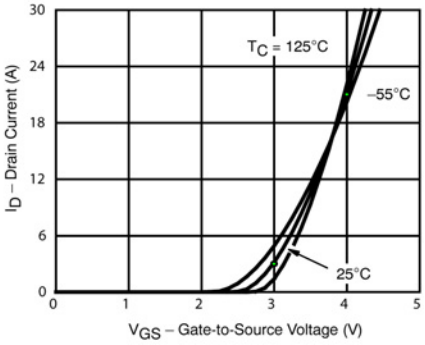


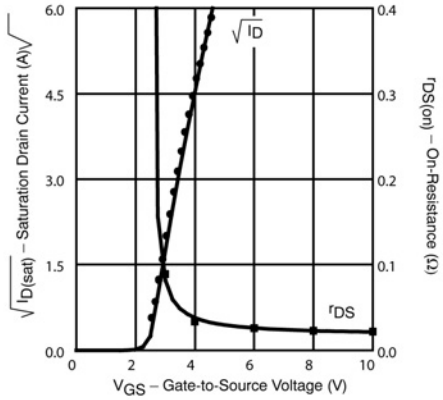
SPECIFICATIONS (T_J = 25°C UNLESS OTHERWISE NOTED)					
Parameter	**Symbol**	**Test Conditions**	**Simulated Data**	**Measured Data**	**Unit**
Static					
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = – 250 μA	1.9		V
On-State Drain Current[a]	$I_{D(on)}$	V_{DS} = –5 V, V_{GS} = –10 V	205		A
Drain-Source On-State Resistance[a]	$r_{DS(on)}$	V_{GS} = –10 V, I_D = –9 A	0.022	0.022	Ω
		V_{GS} = –4.5 V, I_D = –5 A	0.033	0.032	
Forward Transconductance[a]	g_{fs}	V_{DS} = –15 V, I_D = –2.5 A	10	14	S
Diode Forward Voltage[a]	V_{SD}	I_S = –2.9 A, V_{GS} = 0 V	–0.82	–0.80	V
Dynamic[b]					
Total Gate Charge	Q_g	V_{DS} = –15 V, V_{GS} = –10 V, I_D = –9 A	41	42	nC
Gate-Source Charge	Q_{gs}		8.5	8.5	
Gate-Drain Charge	Q_{gd}		7.5	7.5	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = –15 V, R_L = 15 Ω I_D ≅ –1 A, V_{GEN} = –10 V, R_G = 6 Ω	20	18	ns
Rise Time	t_r		28	29	
Turn-Off Delay Time	$t_{d(off)}$		32	65	
Fall Time	t_f		58	27	
Source-Drain Reverse Recovery Time	t_{rr}	I_F = –2.9 A, di/dt = 100 A/μs	40	50	

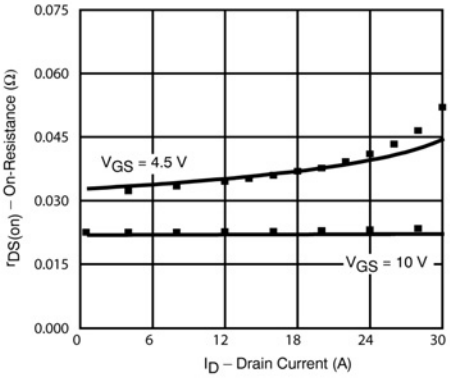
Notes
a. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2%.
b. Guaranteed by design, not subject to production testing.

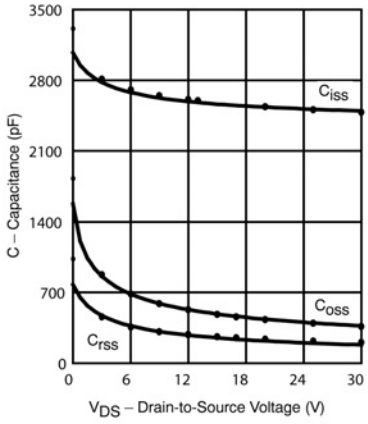
COMPARISON OF MODEL WITH MEASURED DATA (T_J=25°c UNLESS OTHERWISE NOTED)

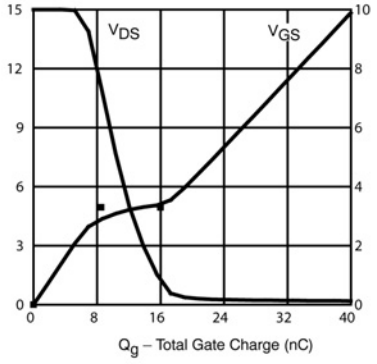












Note: Dots and squares represent measured data.